

5) -403m dB gain at 400MHz

b) a) See next

bi) See next for plot

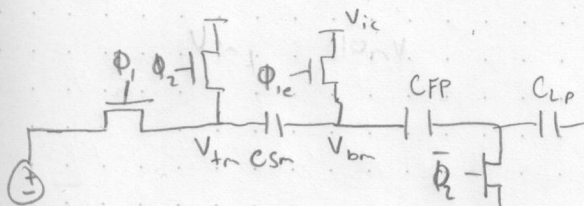
Immediately after Φ_1 rises, V_{cs} drops from 10mV to 9.386mV, an error of 0.614mV

$$V_{cs} \text{ is computed as } V_{cs} = (V_{tm} - V_{bm}) - (V_{tp} - V_{bp})$$

The disturbances on the capacitors are equal in magnitude and not dependent on the input voltage, hence the difference in voltage across them is not affected. The bottom plate sampling technique takes advantage of common mode rejection in the OTA combined with equal charge injection to null the resulting offset.

bii) See next.

biii) Charge injection error headache when Φ_{ie} opens



$$\Phi_{ie} \text{ closed} \Rightarrow V_{bm} = V_{ic} = 0.6V$$

$$\Phi_1 \text{ closed} \Rightarrow V_{tm} = V_{ic} + \frac{V_{id}}{2} = 0.605V$$

$$\Phi_{ie} \text{ mosfet channel} = 30\mu / 0.2\mu Q_{ch} = -WL C_{ox} (V_{dd} - V_{i1} - V_{i2}) = 36fC$$

$$C_{sm} || C_{FP} = 200fF$$

$$\Delta V = \frac{Q_{ch}}{2C} = \frac{36fF}{2 \cdot 200f} = 90.0mV$$

$$113mV \text{ observed}$$